

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT



Hiroyuki SHIMIZU, ET AL.

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U.S. PATENT DOCUMENTS










EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	6,068,918	5/2000	VAN DER VEER ET AL.	428	379	
	AB	4,913,927	4/1990	ANDERSON	427	37	
	AC	4,404,828	9/1983	BLACHFORD	72	42	
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



09/24/01

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO	
	AO	2 245 780	04/25/75	FRANCE		
	AP	2 106 547	04/13/83	GREAT BRITAIN		
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	AZ	Patent Abstracts of Japan, Vol. 010, No. 096 (M-469), April 12, 1986, JP 60 231599, November 18, 1985
	BA	Patent Abstracts of Japan, Vol. 095, No. 001, February 28, 1995, JP 06 285678, October 11, 1994
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Examiner



Date Considered

2/8/02

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.